


<b>Search Notes</b>  	<b>Application/Control No.</b>  10607524	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG ET AL.
	<b>Examiner</b>  Yabut, Diane	<b>Art Unit</b>  3734

SEARCHED			
Class	Subclass	Date	Examiner
606	139, 144, 153	01/04/2008	DY

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search -- see attached Search History, updated 03/02/2007	01/04/2008	DY

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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